

IN THE CLAIMS:

Please note that all claims currently pending and under consideration in the referenced application are shown below, in clean form, for clarity.

Please amend the claims as follows:

1. (Three Times Amended) A semiconductor device assembly, comprising:
a semiconductor die having an active surface having a plurality of bond pads thereon and an opposing second surface, each bond pad of said plurality of bond pads having an upper surface;
at least one projection bump connected to at least a portion of the upper surface of at least one bond pad of said plurality of bond pads on the active surface of said semiconductor die for direct connection to a substrate, said at least one projection bump including one of at least one solder ball and at least one solder bump; and
to a host circuit board, each projection bump of said plurality of projection bumps located on at least a portion of the upper surface of a bond pad of said plurality of bond pads, each projection bump of said plurality of projection bumps including one of a of solder ball and a of solder bump; and
a metallic paddle secured to said second surface of said semiconductor die, said metallic paddle being attached to at least one side rail by at least a plurality of paddle support bars and being attached to a plurality of cross members by said support bars a generally centrally positioned paddle of a lead frame of a plurality of lead frames having side rails and cross members connected to said paddle, said second surface of said semiconductor die being secured to said paddle; and said generally centrally positioned paddle being attached to the side rail by at least a plurality of paddle support bars and being attached to said cross members by said support bars.

2. (Amended) The semiconductor device assembly of claim 1, wherein said at least one projection bump includes a plurality of projections comprising a ball grid array (B.A.) of solder balls.

3. (Amended) The semiconductor device assembly of claim 1, wherein said at least one projection bump comprises at least one ball deposited by a wire bonding machine.

4. (Amended) The semiconductor device assembly of claim 1, wherein said at least one projection bump comprises at least one stud bump deposited by a wire bonding machine.

5. (Previously Amended) The semiconductor device assembly of claim 1, further comprising:
an electrically non-conductive adhesive layer securing said second surface to said generally centrally positioned paddle.

6. The semiconductor device assembly of claim 5, wherein said adhesive layer comprises one of epoxy and polyamide.

7. (Previously Amended) The semiconductor device assembly of claim 1, further comprising:
an electrically conductive adhesive layer securing said second surface of said semiconductor die to said generally centrally positioned paddle.

8. The semiconductor device assembly of claim 7, wherein said electrically conductive adhesive layer comprises a eutectic material.

9. The semiconductor device assembly of claim 7, wherein said electrically conductive adhesive layer comprises a gold-silicon eutectic material.


10. The semiconductor device assembly of claim 7, wherein said electrically conductive adhesive layer comprises a metal-filled polymer, said metal filling comprising a heat conductive material.

11. The semiconductor device assembly of claim 7, wherein said electrically conductive adhesive layer comprises conductive polyamide.

12. The semiconductor device assembly of claim 1, further comprising: said substrate having circuit connections, said plurality of bond pads bonded to said circuit connections.

13. The semiconductor device of claim 12, further comprising: sealant packaging material enclosing a portion of said semiconductor die and covering a portion of said substrate.

14. (Three Times Amended) A semiconductor device assembly, comprising: a semiconductor die having an active surface having at least one bond pad thereon and an opposing second surface, said at least one bond pad having an upper surface; at least one projection bump secured to at least a portion of the upper surface said at least one bond pad on said active surface of said semiconductor die for direct connection to a substrate, said at least one projection bump including one of at least one solder ball and at least one solder bump; and a metal paddle from a lead frame, said second surface of said semiconductor die being attached to said metal paddle; and said metal paddle is attached to at least one side rail by at least



a plurality of paddle support bars and being attached to a plurality of cross members by said support bars.

15. (Amended) The semiconductor device assembly of claim 14, wherein said at least one projection bump comprises a ball grid array (B.A.) of solder balls.

16. (Amended) The semiconductor device assembly of claim 14, wherein said at least one projection bump comprises at least one ball deposited by a wire bonding machine.

17. (Amended) The semiconductor device assembly of claim 14, wherein said at least one projection bump comprises at least one stud bump deposited by a wire bonding machine.

18. The semiconductor device assembly of claim 14, further comprising:
an electrically non-conductive adhesive layer attaching said second surface to said paddle.

19. The semiconductor device assembly of claim 18, wherein said adhesive layer comprises one of epoxy and polyamide.

20. (Previously Amended) The semiconductor device assembly of claim 14, further comprising:
an electrically conductive adhesive layer attaching said second surface to said metal paddle.

21. The semiconductor device assembly of claim 20, wherein said electrically conductive adhesive layer comprises a eutectic material.

22. The semiconductor device of claim 20, wherein said electrically conductive adhesive layer comprises a gold-silicon eutectic material.

23. The semiconductor device assembly of claim 21, wherein said electrically conductive adhesive layer comprises a metal-filled polymer, said metal filling comprising a heat conductor.

24. The semiconductor device assembly of claim 21, wherein said electrically conductive layer comprises conductive polyamide.

25. The semiconductor device assembly of claim 14, further comprising:
a substrate having a plurality of circuit connections, said at least one bond pad connected to at least one circuit connection of said plurality of circuit connections.

26. The semiconductor device assembly of claim 25, further comprising:
sealant packaging covering a portion of said semiconductor die and a portion of said substrate.

27. (Three Times Amended) A semiconductor device assembly, comprising:
a semiconductor die having an active surface having a plurality of bond pads thereon and an opposing second surface, each bond pad of said plurality of bond pads having an upper surface;
a plurality of [projections] projection bumps connected to at least a portion of the upper surfaces of said plurality of bond pads for direct connection to a host circuit board, said plurality of projections including one of a plurality of solder balls and a plurality of solder bumps;
and
a metallic paddle secured to said second surface of said semiconductor die, said metallic paddle being attached to at least one side rail by at least a plurality of paddle support bars and being attached to a plurality of cross members by said support bars.

28. (Amended) The semiconductor device assembly of claim 27, wherein each projection bump of said plurality of projection bumps comprises a ball grid array (B.A.) of solder balls.

29. (Amended) The semiconductor device assembly of claim 27, wherein each projection bump of said plurality of bumps comprises balls deposited by a wire bonding machine.

30. (Amended) The semiconductor device assembly of claim 27, wherein each projection bump of said plurality of projection bumps comprises a plurality of stud bumps deposited by a wire bonding machine.


31. (Previously Amended) The semiconductor device assembly of claim 27, further comprising:
an electrically non-conductive adhesive layer connecting said second surface to said metallic paddle.

32. The semiconductor device assembly of claim 31, wherein said adhesive layer comprises one of epoxy and polyamide.

33. (Previously Amended) The semiconductor device assembly of claim 27, further comprising:
an electrically conductive adhesive layer connecting said second surface to said metallic paddle.

34. The semiconductor device assembly of claim 33, wherein said electrically conductive adhesive layer comprises a eutectic material.

35. The semiconductor device assembly of claim 33, wherein said electrically conductive adhesive layer comprises a gold-silicon eutectic material.

 36. The semiconductor device assembly of claim 33, wherein said electrically conductive adhesive layer comprises a metal-filled polymer, said metal filling comprising a heat conductive material.

37. The semiconductor device assembly of claim 33, wherein said electrically conductive adhesive layer comprises conductive polyamide.

38. The semiconductor device of claim 27, further comprising:
a substrate having a plurality of circuit connections, said plurality of bond pads connected to said plurality of circuit connections.

39. The semiconductor device assembly of claim 38, further comprising:
sealant packaging covering a portion of said semiconductor die and a portion of said substrate.
